

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
Jeff Natalini		2858		

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	B	US-6,747,457	06-2004	Suzuki, Kouhei	324/433
	C	US-5,485,090	01-1996	Stephens, Charles S.	324/433
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NON-PATENT DOCUMENTS

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	U	Ichimura et al. "Measuring the Internal Resistance of a Cell in Assembled Batteries", 1996 IEEE, pgs 784-791.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.